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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| In re United States Patent Application of: |) Docket No.: 2771-688 |
| Applicants: KING, Mackenzie, et al. |) Conf. No.: 7009 |
| Application No.: 10/722,174 |) Art Unit: 1742 |
| Date Filed: November 25, 2003 |) Examiner: Nicholas A. Smith |
| Title: ON-WAFER ELECTROCHEMICAL DEPOSITION PLATING METROLOGY PROCESS AND APPARATUS |) Customer No.: 23448 |

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Steven J. Hultquist

September 4, 2007

Date

**RESPONSE TO JUNE 5, 2007 OFFICE ACTION IN U.S. PATENT APPLICATION NO.
10/722,174**

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

2771-688

This responds to the June 5, 2007 Office Action in the above-identified application.

A listing of the claims of the application is set out in **Section I (Listing of the Claims)** beginning at page 3 hereof.

Remarks concerning the substance of the June 5, 2007 Office Action are set out in **Section II (Remarks)** beginning at page 9 hereof.